

<b>Search Notes</b>	<b>Application/Control No.</b>	<b>Applicant(s)/Patent Under Reexamination</b>
	10065546	NEIMAN ET AL.
	<b>Examiner</b>	<b>Art Unit</b>
	Wai, Eric C	2195

### SEARCHED

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>
718	105	12/13/2006	ECW
709	104	12/13/2006	ECW

### SEARCH NOTES

<b>Search Notes</b>	<b>Date</b>	<b>Examiner</b>
Inventor's Name Search	12/13/2006	ECW
East Search	12/13/2006	ECW

### INTERFERENCE SEARCH

<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>